

Volume 18, Number 2

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# Microscopy AND Microanalysis



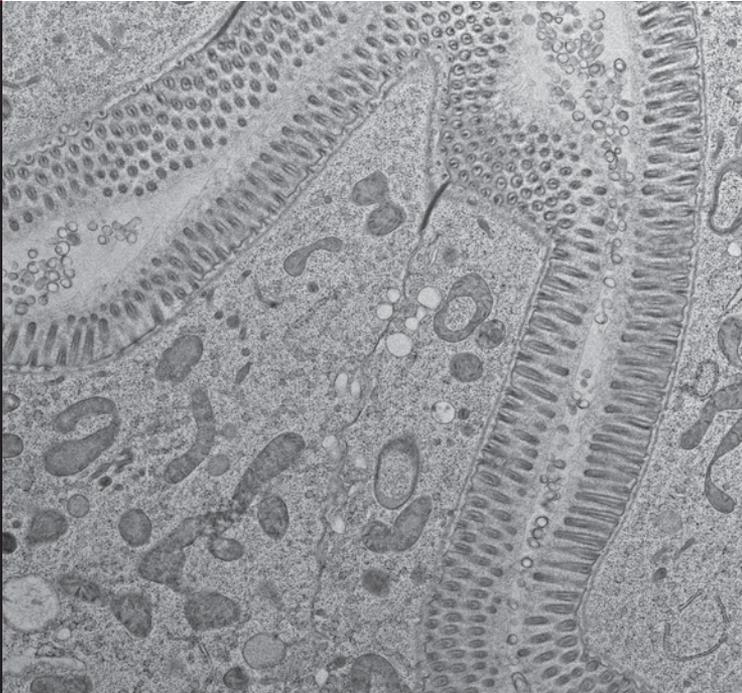
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<sup>1</sup>Delaware Biotechnology Institute Bio-Imaging Center <sup>2</sup>University of Pennsylvania



Smithsonian National Mineral Collection Preparation: Cut and polished with the Leica EM TPX. Scott Wight<sup>1</sup>, Ed Vicenzi<sup>2</sup>, Doug Meier<sup>3</sup>, and Kurt Benkstein<sup>4</sup>  
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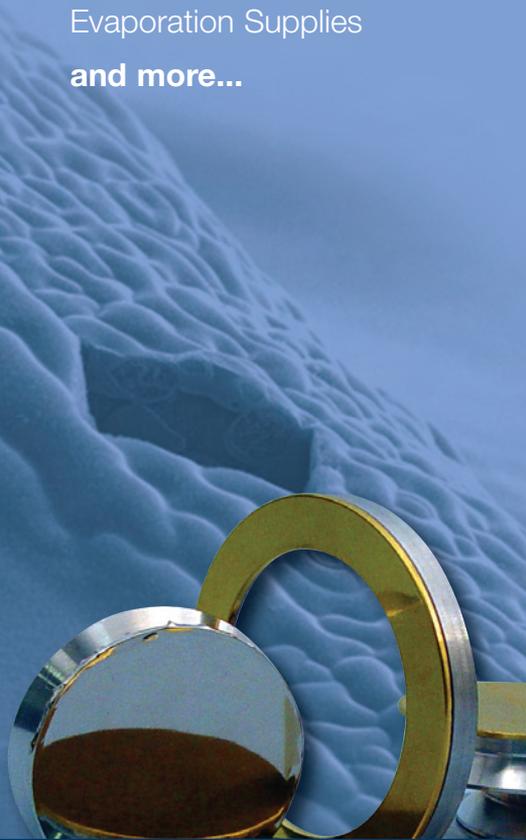


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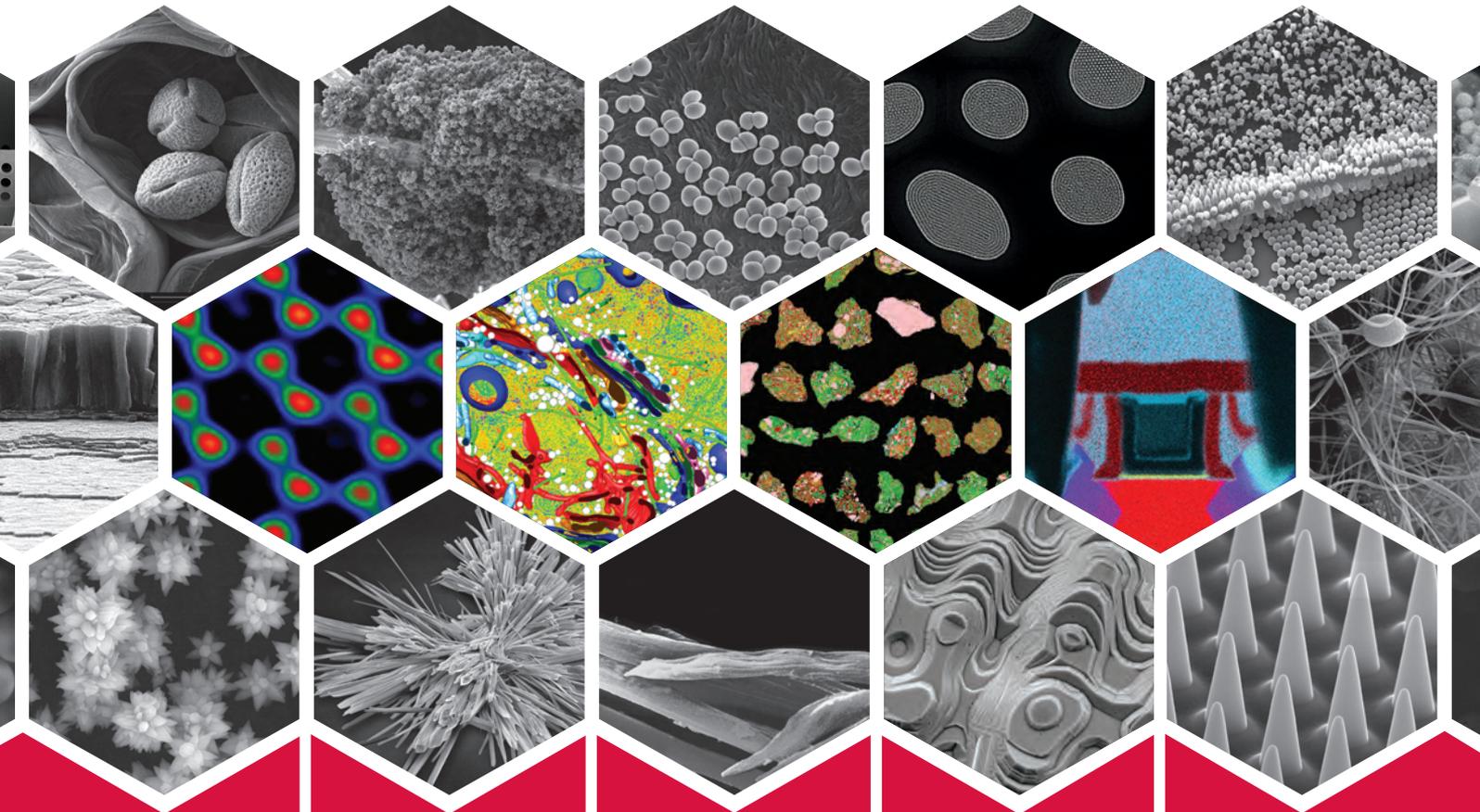


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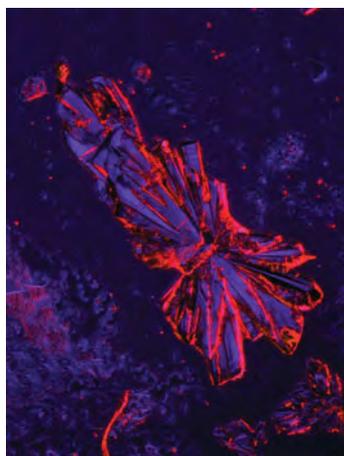
April 2012

## MATERIALS APPLICATIONS

- Microfluorescence Analysis of Nanostructuring Inhomogeneity in Optical Fibers with Embedded Gallium Oxide Nanocrystals 259  
*Valery M. Mashinsky, Nikita M. Karatun, Vladimir A. Bogatyrev, Vladimir N. Sigaev, Nikita V. Golubev, Elena S. Ignat'eva, Roberto Lorenzi, Maria Cristina Mozzati, Alberto Paleari, and Evgeny M. Dianov*
- Three-Dimensional Characterization of Pigment Dispersion in Dried Paint Films Using Focused Ion Beam–Scanning Electron Microscopy 266  
*Jui-Ching Lin, William Heeschen, John Reffner, and John Hook*
- Microstructural Characterization of Next Generation Nuclear Graphites 272  
*Chinnathambi Karthik, Joshua Kane, Darryl P. Butt, William E. Windes, and Rick Ubic*

## BIOLOGICAL AND BIOMEDICAL APPLICATIONS

- Characterization of Micro- and Nanophase Separation of Dentin Bonding Agents by Stereoscopy and Atomic Force Microscopy 279  
*Manuel Toledano, Monica Yamauti, Estrella Osorio, Francesca Monticelli, and Raquel Osorio*
- Scanning Electron Microscopy and Roughness Study of Dental Composite Degradation 289  
*Luís Eduardo Silva Soares, Louise Ribeiro Cortez, Raquel de Oliveira Zarur, and Airton Abrahão Martin*
- Microstructural Evaluation of Boron Free and Boron Containing Heat-Treated Ti-35Nb-7.2Zr-5.7Ta Alloy 295  
*Pallab Majumdar*
- Bee (*Apis mellifera*) Venom Produced Toxic Effects of Higher Amplitude in Rat Thoracic Aorta than in Skeletal Muscle—An Ultrastructural Study 304  
*Adrian Florea and Constantin Crăciun*
- Alterations in the Fat Body Cells of *Rhinocricus padbergi* (Diplopoda) Resulting from Exposure to Substrate Containing Sewage Sludge 317  
*Raphael Bastão de Souza and Carmem Silvia Fontanetti*
- Bioconjugated and Cross-Linked Bionanostructures for Bifunctional Immunohistochemical Labeling 324  
*Rian Say, Gözde Aydoğan Kılıç, Ayça Atılır Özcan, Deniz Hür, Filiz Yılmaz, Adil Denizli, and Arzu Ersöz*
- A Negative Stain for Electron Microscopic Tomography 331  
*Andrea Fera, Jane E. Farrington, Joshua Zimmerberg, and Thomas S. Reese*



**On the Cover:** Variable phase dark-field contrast image of ascorbic acid crystal. For further information, see Piper and Piper, pages 343–352.

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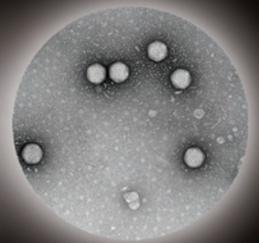
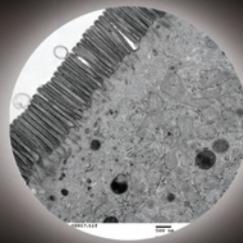
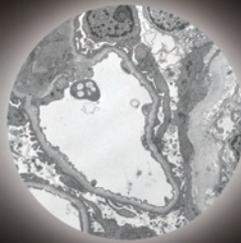
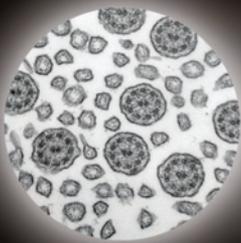
## TECHNIQUES AND SOFTWARE DEVELOPMENT

- Fully Automated Measurement of the Modulation Transfer Function of Charge-Coupled Devices above the Nyquist Frequency 336  
*Wouter Van den Broek, Sandra Van Aert, and Dirk Van Dyck*
- Variable Phase Dark-Field Contrast—A Variant Illumination Technique for Improved Visualizations of Transparent Specimens 343  
*Timm Piper and Jörg Piper*
- Calibration of Piezoelectric Positioning Actuators Using a Reference Voltage-to-Displacement Transducer Based on Quartz Tuning Forks 353  
*Andres Castellanos-Gomez, Carlos R. Arroyo, Nicolás Agrait, and Gabino Rubio-Bollinger*
- A New Approach to the Determination of Concentration Profiles in Atom Probe Tomography 359  
*Peter J. Felfer, Baptiste Gault, Gang Sha, Leigh Stephenson, Simon P. Ringer, and Julie M. Cairney*
- Possibility of Scanning Electron Microscope Observation and Energy-Dispersive X-Ray Analysis in Microscale Region of Insulating Samples Using Diluted Ionic Liquid 365  
*Susumu Imashuku, Tetsuo Kawakami, Long Ze, and Jun Kawai*
- Dependence of the Electron Beam Energy and Types of Surface to Determine EBSD Indexing Reliability in Yttria-Stabilized Zirconia 371  
*Laxmikant V. Saraf*
- Improved Focused Ion Beam Target Preparation of (S)TEM Specimen—A Method for Obtaining Ultrathin Lamellae 379  
*Lorenz Lechner, Johannes Biskupek, and Ute Kaiser*
- Highly Reproducible Secondary Electron Imaging under Electron Irradiation Using High-Pass Energy Filtering in Low-Voltage Scanning Electron Microscopy 385  
*Daisuke Tsurumi, Kotaro Hamada, and Yuji Kawasaki*
- Dimensional Quantification of Embedded Voids or Objects in Three Dimensions Using X-Ray Tomography 390  
*Brian M. Patterson, Juan P. Escobedo-Diaz, Darcie Dennis-Koller, and Ellen Cerreta*
- Improved Signal-to-Noise Ratio in Laboratory-Based Phase Contrast Tomography 399  
*Matthieu N. Boone, Yoni De Witte, Manuel Dierick, Ana Almeida, and Luc Van Hoorebeke*
- Electron Diffraction Based Analysis of Phase Fractions and Texture in Nanocrystalline Thin Films, Part III: Application Examples 406  
*J.L. Lábár, M. Adamik, B.P. Barna, Zs. Czigány, Zs. Fogarassy, Z.E. Horváth, O. Geszti, F. Misják, J. Morgiel, G. Radnóczy, G. Sáfrán, L. Székely, and T. Szüts*
- CALENDAR OF MEETINGS AND COURSES** 421



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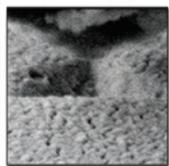
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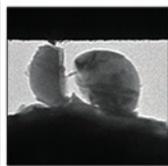
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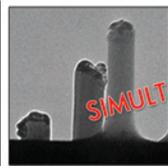
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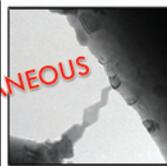
TENSILE



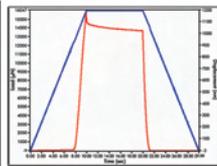
BEND



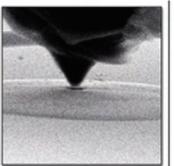
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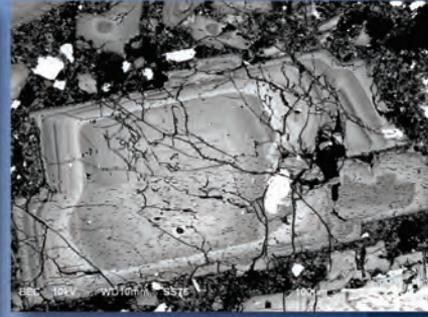
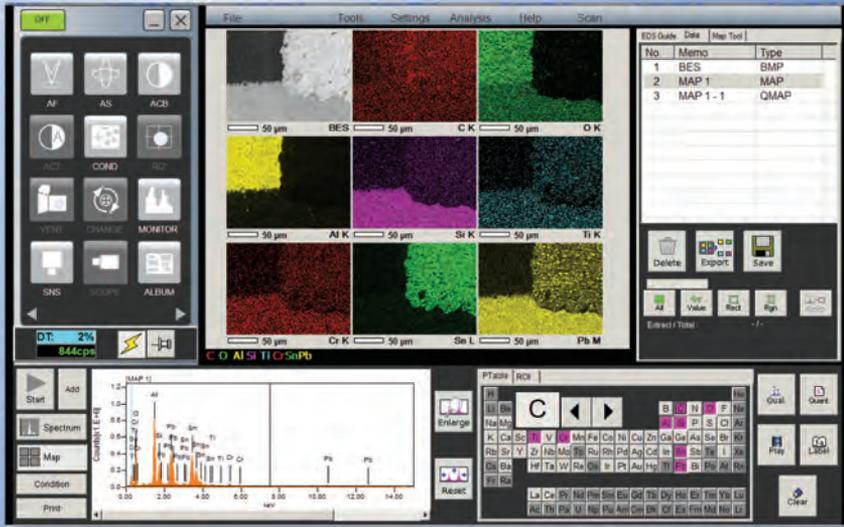
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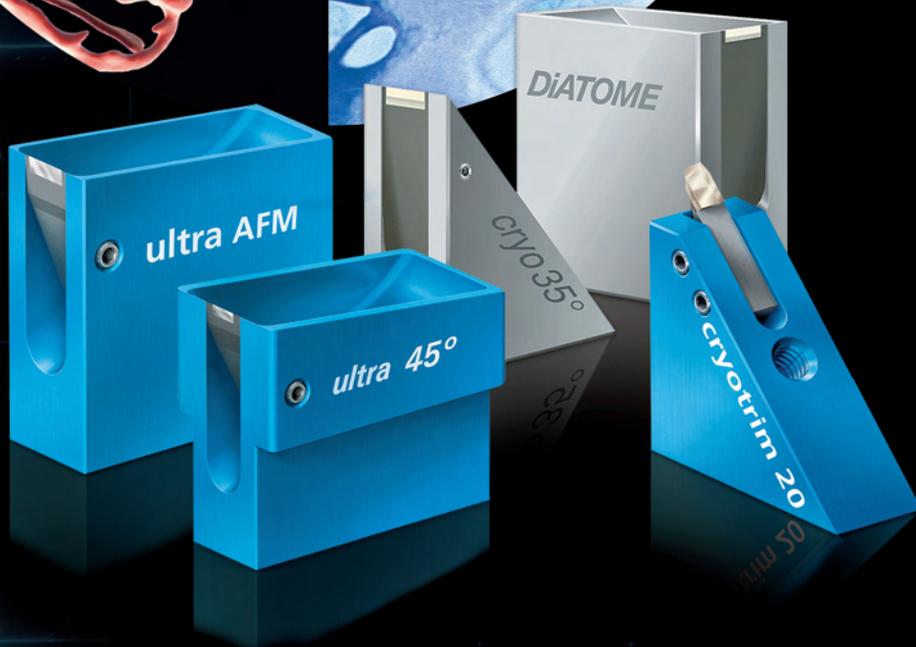
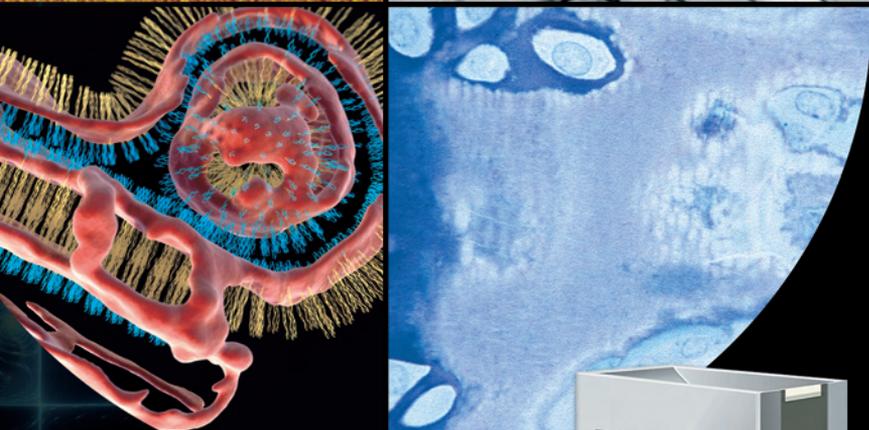
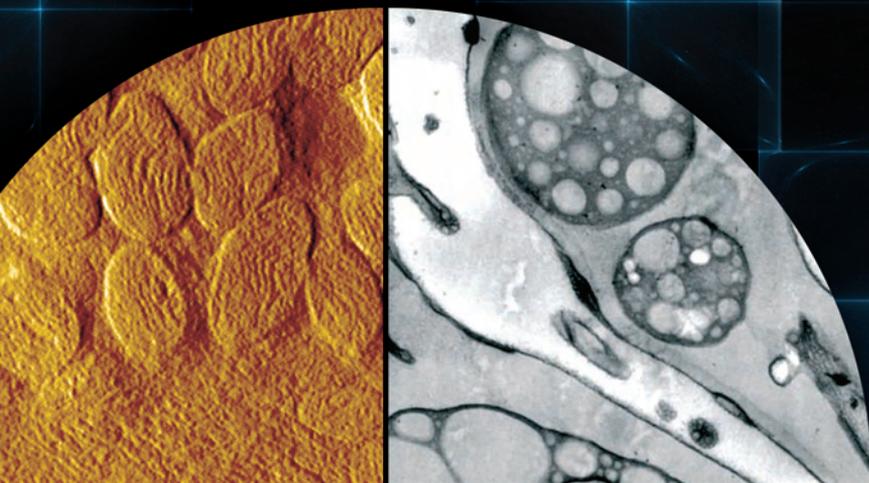
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